Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/611,295	SHEI, STEVEN M.	
Examiner	Art Unit	_
Joseph M. Pelham	3742	

	SEAR	CHED	
Class	Subclass	Date	Examiner
			·
•			
<del>-</del>			
			<u>-</u>
	1	-	

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
	8/19/2006	JP			
1					
	<u> </u>	Subclass Date			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See update history	8/19/2006	JP		